

IN THE CLAIMS

We claim:

1. A structure comprising:
 - a first set of features disposed in the scribeline, said first set of features being a subset of product features; and
 - a second set of features disposed adjacent to said first set of features, said second set occupying a smaller area than said first set, said second set being similar to said first set, said second set being distinguishable from surrounding structures.
2. The structure of claim 1 wherein critical dimension (CD) is measured on said first set of features.
3. The structure of claim 1 wherein said first set of features and said second set of features differ in spaces between features.
4. The structure of claim 1 wherein said first set of features and said second set of features differ in linewidths of features.
5. The structure of claim 1 wherein said first set of features and said second set of features have the same pitch for features.

6. The structure of claim 1 wherein said first set of features comprises a first array of holes.

7. The structure of claim 6 wherein said first array of holes comprises a 5-by-5 square array of holes.

8. The structure of claim 6 wherein said second set of features comprises a second array of holes.

9. The structure of claim 8 wherein said second array of holes differs from said first array of holes in size of array.

10. The structure of claim 8 wherein said second array of holes differs from said first array of holes in space between holes.

11. The structure of claim 8 wherein said second array of holes differs from said first array of holes in linewidths of holes.

12. A method comprising:

extracting a subset from product features to form a first set of features;

extracting a small portion from said first set of features to form a

template;

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O/C for 7/19/21
PE 10/27/03

transforming said template into a second set of features by
rotating said template;
scaling spaces between features in said template;
scaling linewidths of features in said template;
merging said first set and said second set of features to form a test
structure.

13. The method of claim 12 wherein critical dimension (CD) is measured on
said first set of features.

14. A method comprising:

storing a reference image of a test structure, said reference image
comprising a first set of features and a second set of features,
said first set of features being a subset of product features,
said second set of features disposed adjacent to said first set of
features, said second set occupying a smaller area than said first set, said second
set being similar to said first set, said second set being distinguishable from
surrounding structures;

capturing a test image of a sample, said test image having a plurality
of portions;

performing pattern recognition of each of said portions relative to said
reference image;

evaluating similarity of each of said portions to said reference image;

determining a score for each of said portions;

ranking said portions from highest score to lowest score; and

determining location on said sample of said portion with highest score.

